



FQB30N06L / FQI30N06L

60V LOGIC N-Channel MOSFET

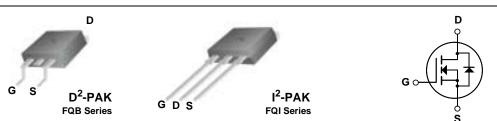
General Description

These N-Channel enhancement mode power field effect transistors are produced using Fairchild's proprietary, planar stripe, DMOS technology.

This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for low voltage applications such as automotive, DC/DC converters, and high efficiency switching for power management in portable and battery operated products.

Features

- $\sim 32A, 60V, R_{DS(on)} = 0.035\Omega @V_{GS} = 10 V$
- Low gate charge (typical 15 nC)
- Low Crss (typical 50 pF)
- Fast switching
- 100% avalanche tested
- · Improved dv/dt capability
- · 175°C maximum junction temperature rating
- RoHS Compliant



Absolute Maximum Ratings $T_C = 25^{\circ}C$ unless otherwise noted

Symbol	Parameter		FQB30N06L / FQI30N06L	Units
V _{DSS}	Drain-Source Voltage		60	V
I _D	Drain Current - Continuous (T _C = 25°C) - Continuous (T _C = 100°C)		32	Α
			22.6	Α
I _{DM}	Drain Current - Pulsed	(Note 1)	128	Α
V _{GSS}	Gate-Source Voltage		± 20	V
E _{AS}	Single Pulsed Avalanche Energy	(Note 2)	350	mJ
I _{AR}	Avalanche Current	(Note 1)	32	А
E _{AR}	Repetitive Avalanche Energy	(Note 1)	7.9	mJ
dv/dt	Peak Diode Recovery dv/dt	(Note 3)	7.0	V/ns
P_{D}	Power Dissipation (T _A = 25°C) *		3.75	W
	Power Dissipation (T _C = 25°C) - Derate above 25°C		79	W
			0.53	W/°C
T _J , T _{STG}	Operating and Storage Temperature Range		-55 to +175	°C
T _L	Maximum lead temperature for soldering purposes, 1/8" from case for 5 seconds		300	°C

Thermal Characteristics

Symbol	Parameter	Тур	Max	Units
$R_{\theta JC}$	Thermal Resistance, Junction-to-Case		1.90	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient *		40	°C/W
$R_{\theta JA}$	Thermal Resistance, Junction-to-Ambient		62.5	°C/W

^{*} When mounted on the minimum pad size recommended (PCB Mount)

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Cha	aracteristics					
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} = 0 V, I _D = 250 μA	60			V
ΔBV _{DSS} / ΔΤ _J	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, Referenced to 25°C		0.06		V/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 60 V, V _{GS} = 0 V			1	μΑ
		V _{DS} = 48 V, T _C = 150°C			10	μΑ
I _{GSSF}	Gate-Body Leakage Current, Forward	V _{GS} = 20 V, V _{DS} = 0 V			100	nA
I _{GSSR}	Gate-Body Leakage Current, Reverse	V _{GS} = -20 V, V _{DS} = 0 V			-100	nA
On Cha	racteristics					
V _{GS(th)}	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_{D} = 250 \mu\text{A}$	1.0		2.5	V
R _{DS(on)}	Static Drain-Source	V _{GS} = 10 V, I _D = 16 A		0.027	0.035	
D3(0H)	On-Resistance	V _{GS} =5 V, I _D =16 A		0.035		Ω
g _{FS}	Forward Transconductance	V _{DS} = 25 V, I _D = 16 A (Note 4)		24		S
C _{iss}	Input Capacitance Output Capacitance	$V_{DS} = 25 \text{ V}, V_{GS} = 0 \text{ V},$ f = 1.0 MHz		800 270	1040 350	pF pF
C _{rss}	Reverse Transfer Capacitance			50	65	pF
Switchi	ing Characteristics					
t _{d(on)}	Turn-On Delay Time	V _{DD} = 30 V, I _D = 16 A,		15	40	ns
t _r	Turn-On Rise Time	55 5		210	430	ns
t _{d(off)}	Turn-Off Delay Time	G		60	130	ns
t _f	Turn-Off Fall Time	(Note 4, 5)		110	230	ns
	Total Gate Charge	V _{DS} = 48 V, I _D = 32 A,		15	20	nC
Q_{gs}	Gate-Source Charge	V _{GS} = 5 V		3.5		nC
Q_{gd}	Gate-Drain Charge	(Note 4, 5)		8.5		nC
$\begin{array}{c} t_r \\ t_{d(off)} \\ t_f \\ Q_g \\ Q_{gs} \\ Q_{gd} \end{array}$	Turn-Off Delay Time Turn-Off Fall Time Total Gate Charge Gate-Source Charge	$R_G = 25 \Omega$ (Note 4, 5) $V_{DS} = 48 \text{ V}, I_D = 32 \text{ A}, V_{GS} = 5 \text{ V}$		60 110 15 3.5	130 230 20 	
.						
	Source Diode Characteristics at				22	۸
l _S	Maximum Continuous Drain-Source Diode Forward Current Maximum Pulsed Drain-Source Diode Forward Current				32	A
I _{SM}					128	A
V _{SD}	Drain-Source Diode Forward Voltage	V _{GS} = 0 V, I _S = 32 A			1.5	V
t _{rr}	Reverse Recovery Time	$V_{GS} = 0 \text{ V, } I_S = 32 \text{ A,}$		60		ns
Q_{rr}	Reverse Recovery Charge	$dI_F / dt = 100 A/\mu s$ (Note 4)		90		nC

- **Notes:**1. Repetitive Rating : Pulse width limited by maximum junction temperature 2. L = 400μH, I_{AS} = 32A, V_{DD} = 25V, R_{G} = 25 Ω, Starting T_{J} = 25°C 3. I_{SD} ≤ 32A, di/dt ≤ 300A/us, V_{DD} ≤ BV_{DSS}, Starting T_{J} = 25°C 4. Pulse Test : Pulse width ≤ 300us, Duty cycle ≤ 2% 5. Essentially independent of operating temperature

Typical Characteristics

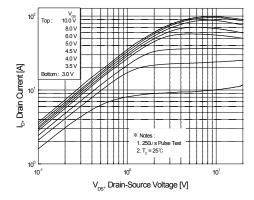


Figure 1. On-Region Characteristics

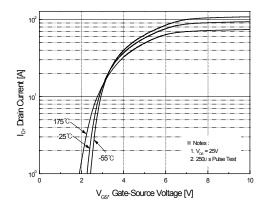


Figure 2. Transfer Characteristics

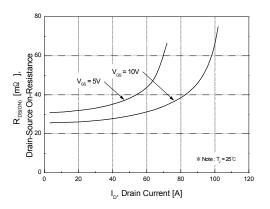


Figure 3. On-Resistance Variation vs. Drain Current and Gate Voltage

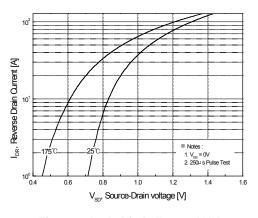


Figure 4. Body Diode Forward Voltage Variation vs. Source Current and Temperature

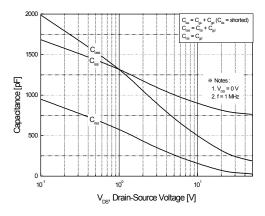


Figure 5. Capacitance Characteristics

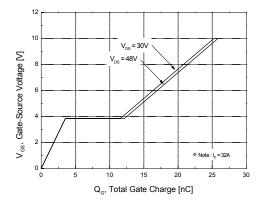
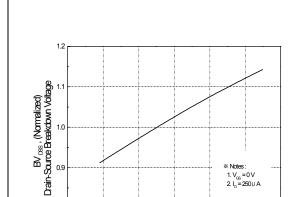


Figure 6. Gate Charge Characteristics

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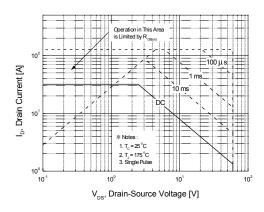
Typical Characteristics (Continued)

Figure 7. Breakdown Voltage Variation vs. Temperature

T,, Junction Temperature [°C]

150

Figure 8. On-Resistance Variation vs. Temperature



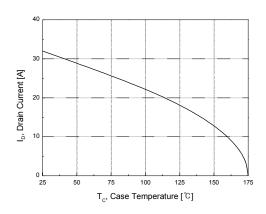


Figure 9. Maximum Safe Operating Area

Figure 10. Maximum Drain Current vs Case Temperature

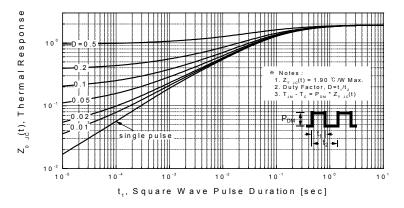
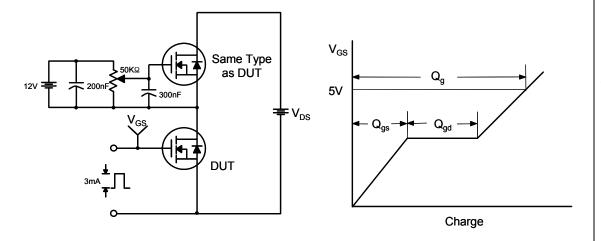


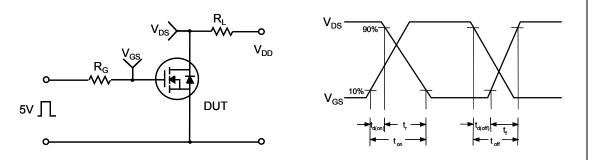
Figure 11. Transient Thermal Response Curve

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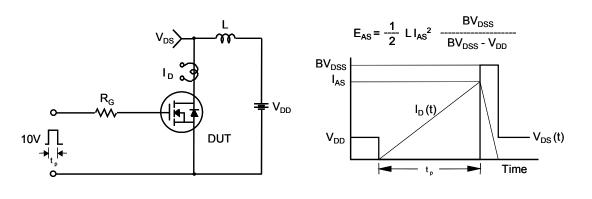
Gate Charge Test Circuit & Waveform



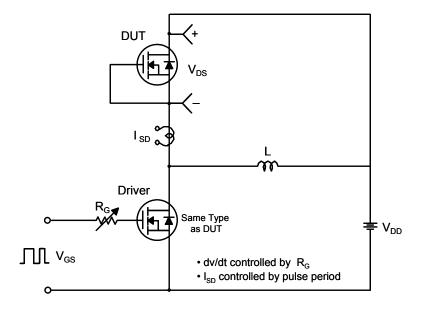
Resistive Switching Test Circuit & Waveforms

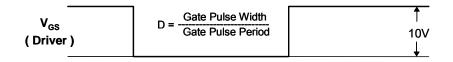


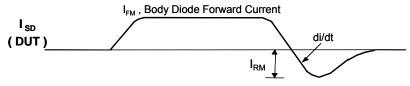
Unclamped Inductive Switching Test Circuit & Waveform



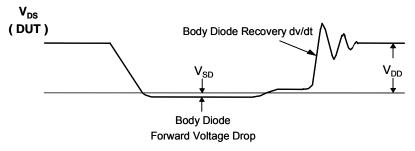
Peak Diode Recovery dv/dt Test Circuit & Waveforms

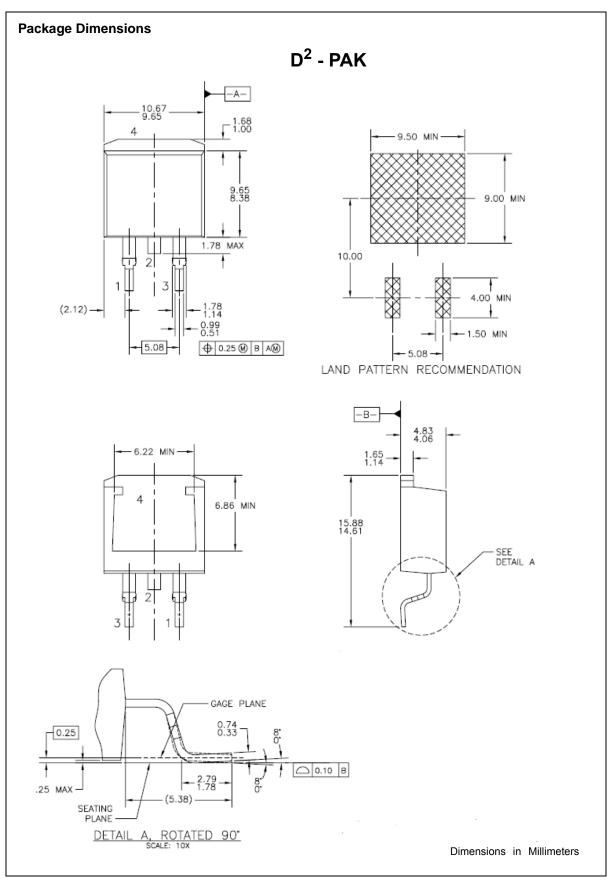


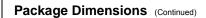




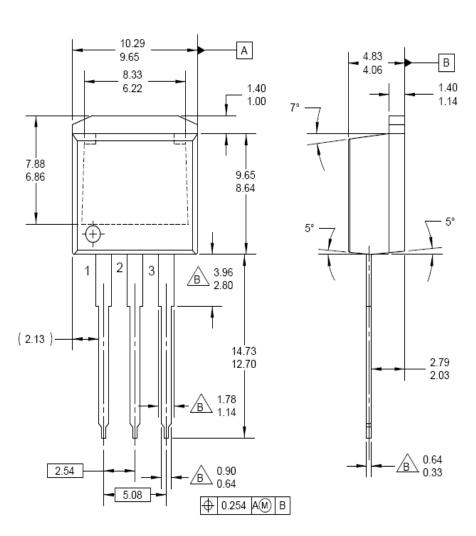
Body Diode Reverse Current







I² - PAK



Dimensions in Millimeters





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